

Notice of References Cited

Application/Control No.

10/573,810

Applicant(s)/Patent Under
Reexamination
MIYADERA ET AL.

Examiner

JOHN M. BEDTELYON

Art Unit

2874

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0202746	10-2003	Hanashima, Naoki	385/45
*	B	US-7,302,138	11-2007	Lu, Hung-Chih	385/37
*	C	US-7,088,889	08-2006	Takahashi et al.	385/43
*	D	US-6,970,625	11-2005	Johannessen et al.	385/45
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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